## SN74CBT3257 QUADRUPLE 2-BIT TO 1-BIT FET MULTIPLEXER/DEMULTIPLEXER

SCDS017F - MAY 1995 - REVISED MAY 1997

16 V<u>C</u>C

15 0E

14 🛛 4B1

13 4B2

12 4A

11 🛛 3B1

10 3B2

9 3A

D, DB, DBQ, OR PW PACKAGE (TOP VIEW)

S

1B1 [

1B2 🛛 3

1A 4

2B1 [

2B2 6

2A 🛛 7

GND 8

2

5

- Functionally Equivalent to QS3257
- 5-Ω Switch Connection Between Two Ports
- TTL-Compatible Control Input Levels
  Package Options Include Plastic Small-Outline (D), Shrink Small-Outline
- (DB), Quarter-Size Small-Outline (DBQ), and Thin Shrink Small-Outline (PW) Packages

#### description

The SN74CBT3257 is a quadruple 2-bit to 1-bit high-speed TTL-compatible FET demultiplexer/ multiplexer. The low on-state resistance of the switch allows connections to be made with minimal propagation delay.

Output-enable  $(\overline{OE})$  and select-control (S) select the appropriate B1 and B2 outputs for the A-input data.

The SN74CBT3257 is characterized for operation from -40°C to 85°C.

S	OE	FUNCTION
Х	Н	Disconnect
L	L	A = B1
н	L	A = B2

#### FUNCTION TABLE



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

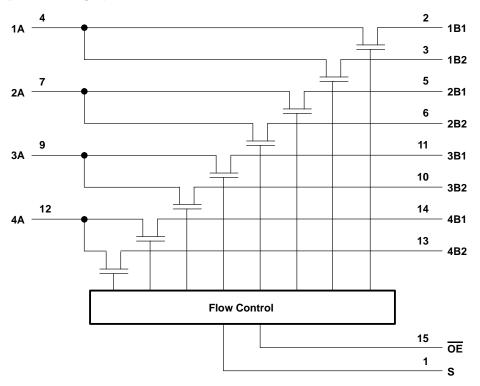


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### logic diagram (positive logic)



### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, V <sub>CC</sub> Input voltage range, V <sub>I</sub> (see Note 1)		
Continuous channel current		
Input clamp current, I <sub>K</sub> (V <sub>I/O</sub> < 0)		–50 mA
Package thermal impedance, $\theta_{JA}$ (see Note 2)	: D package	113°C/W
	DB package	131°C/W
	DBQ package	139°C/W
	PW package	149°C/W
Storage temperature range, T <sub>stg</sub>		–65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.

### recommended operating conditions

		MIN	MAX	UNIT
VCC	Supply voltage	4	5.5	V
VIH	High-level control input voltage	2		V
VIL	Low-level control input voltage		0.8	V
т <sub>А</sub>	Operating free-air temperature	-40	85	°C



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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PAR	AMETER		TEST CONDIT	TIONS	MIN	TYP†	MAX	UNIT
VIK		V <sub>CC</sub> = 4.5 V,	lı = -18 mA				-1.2	V
lj		V <sub>CC</sub> = 5.5 V,	$V_{I} = 5.5 V \text{ or GND}$				±1	μΑ
ICC		V <sub>CC</sub> = 5.5 V,	I <sub>O</sub> = 0,	$V_{I} = V_{CC}$ or GND			3	μΑ
$\Delta I_{CC}^{\ddagger}$	Control pins	V <sub>CC</sub> = 5.5 V,	One input at 3.4 V,	Other inputs at $V_{CC}$ or GND			2.5	mA
Ci	Control pins	V <sub>I</sub> = 3 V or 0				3.5		pF
C <sub>io(OFF)</sub>	A port	V <sub>O</sub> = 3 V or 0,	<b></b>			6.5		~F
	B port		$\overline{OE} = V_{CC}$			4		pF
8		V <sub>CC</sub> = 4 V,	V <sub>I</sub> = 2.4 V,	lj = 15 mA		14	20	
			N/4 0	lj = 64 mA		5	7	Ω
r <sub>on</sub> §		$V_{CC} = 4.5 V$ $V_{I} = 0$	V <sub>1</sub> = 0	lj = 30 mA		5	7	52
			V <sub>I</sub> = 2.4 V,	lj = 15 mA		10	15	

<sup>†</sup> All typical values are at  $V_{CC}$  = 5 V,  $T_A$  = 25°C.

<sup>‡</sup>This is the increase in supply current for each input that is at the specified TTL voltage level rather than V<sub>CC</sub> or GND.

§ Measured by the voltage drop between the A and the B terminals at the indicated current through the switch. On-state resistance is determined by the lowest voltage of the two (A or B) terminals.

# switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

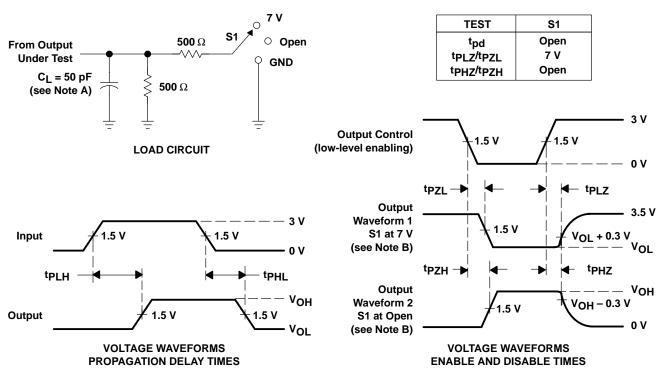
PARAMETER	FROM (INPUT)	то (ОИТРИТ)	V <sub>CC</sub> = 5 V ± 0.5 V		V <sub>CC</sub> = 4 V	UNIT
			MIN	MAX	MIN M	x
t <sub>pd</sub> ¶	A or B	B or A		0.25	0.	25 ns
<sup>t</sup> pd	S	A or B	1.6	5	Ę	.5 ns
<sup>t</sup> en	S	A or B	1.6	5.2	Ę	.7
	OE		1.8	5.1	Ę	.6 ns
<sup>t</sup> dis	S	A or B	1	5	Ę	.2
	OE		2.2	5.5	Ę	.5 ns

This parameter is warranted but not production tested. The propagation delay is based on the RC time constant of the typical on-state resistance of the switch and a load capacitance of 50 pF, when driven by an ideal voltage source (zero output impedance).



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#### PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

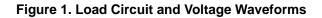
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>f</sub>  $\leq$  2.5 ns, t<sub>f</sub>  $\leq$  2.5 ns. D. The outputs are measured one at a time with one transition per measurement.

D. The outputs are measured one at a time with

E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ . F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .

G. tpLH and tpHL are the same as  $t_{pd}$ .





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